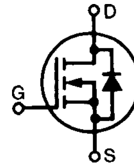
HiPerFET™ Power MOSFETs

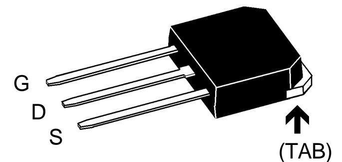
IXFJ 13N50

V_{DSS}	= 500	V
$I_{D(cont)}$	= 13	A
$R_{DS(on)}$	= 0.4	Ω
t_{rr}	≤ 250	ns

N-Channel Enhancement Mode
High dv/dt, Low t_{rr}, HDMOS™ Family



Symbol	Test Conditions	Maximum Ratings	
V_{DSS}	T_J = 25°C to 150°C	500	V
V_{DGR}	T_J = 25°C to 150°C; R_{GS} = 1 MΩ	500	V
V_{GS}	Continuous	±20	V
V_{GSM}	Transient	±30	V
I_{D25}	T_C = 25°C	13	A
I_{DM}	T_C = 25°C, pulse width limited by T_{JM}	52	A
I_{AR}	T_C = 25°C	13	A
E_{AR}	T_C = 25°C	18	mJ
dv/dt	$I_S \le I_{DM}$, di/dt ≤ 100 A/µs, $V_{DD} \le V_{DSS}$, $T_J \le 150$°C, R_G = 2 Ω	5	V/ns
P_D	T_C = 25°C	180	W
T_J		-55 ... +150	°C
T_{JM}		150	°C
T_{stg}		-55 ... +150	°C
T_L	1.6 mm (0.062 in.) from case for 10 s	300	°C
Weight		5	g



G = Gate, D = Drain,
S = Source, TAB = Drain

Symbol	Test Conditions		Characteristic Values (T_J = 25°C, unless otherwise specified) min.	typ.	max.	
V_{DSS}	V_{GS} = 0 V, I_D = 250 µA		500			V
$V_{GS(th)}$	V_{DS} = V_{GS}, I_D = 2.5 mA		2		4	V
I_{GSS}	V_{GS} = ±20 V_{DC}, V_{DS} = 0				±100	nA
I_{DSS}	V_{DS} = 0.8 • V_{DSS} V_{GS} = 0 V	T_J = 25°C T_J = 125°C			200 1	µA mA
$R_{DS(on)}$	V_{GS} = 10 V, I_D = 0.5 • I_{D25} Pulse test, t ≤ 300 µs, duty cycle d ≤ 2 %				0.4	Ω

Features

- Low profile, high power package
- Long creep and strike distances
- Easy up-grade path for TO-220 designs
- Low $R_{DS(on)}$ HDMOS™ process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
  - easy to drive and to protect
- Fast intrinsic Rectifier

Applications

- DC-DC converters
- Synchronous rectification
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- AC motor control
- Temperature and lighting controls
- Low voltage relays

Advantages

- High power, low profile package
- Space savings
- High power density

IXYS reserves the right to change limits, test conditions, and dimensions. 98578 (2/99)

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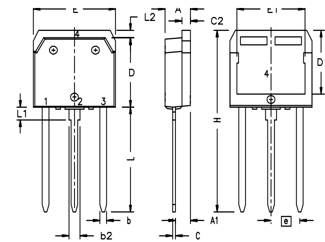
Symbol	Test Conditions	Characteristic Values (T_J = 25°C, unless otherwise specified) min.	typ.	max.	
g_{fs}	V_{DS} = 10 V; I_D = 0.5 I_{D25}, pulse test	7.5	9.0		S
C_{iss}	V_{GS} = 0 V, V_{DS} = 25 V, f = 1 MHz		2800		pF
C_{oss}			300		pF
C_{rss}			70		pF
$t_{d(on)}$	V_{GS} = 10 V, V_{DS} = 0.5 • V_{DSS}, I_D = 0.5 • I_{D25}, R_G = 4.7 Ω (External)		18	30	ns
t_r			27	40	ns
$t_{d(off)}$			76	100	ns
t_f			32	60	ns
$Q_{g(on)}$	V_{GS} = 10 V, V_{DS} = 0.5 • V_{DSS}, I_D = 0.5 • I_{D25}		110	120	nC
Q_{gs}			15	25	nC
Q_{gd}			40	50	nC
R_{thJC}				0.7	K/W
R_{thCK}			0.25		K/W

Source-Drain Diode

Symbol	Test Conditions		Characteristic Values (T_J = 25°C, unless otherwise specified) min.	typ.	max.	
I_S	V_{GS} = 0 V				13	A
I_{SM}	Repetitive; pulse width limited by T_{JM}				52	A
V_{SD}	$I_F = I_S$, V_{GS} = 0 V, Pulse test, t ≤ 300 µs, duty cycle d ≤ 2 %				1.5	V
t_{rr}	$I_F = I_S$, -di/dt = 100 A/µs, V_R = 100 V	T_J = 25°C			250	ns
		T_J = 125°C			350	ns
Q_{RM}		T_J = 25°C		0.6		µC
		T_J = 125°C		1.25		µC
I_{RM}		T_J = 25°C		9		A
		T_J = 125°C		15		A

TO-268 Outline



All metal area are solder plated
1 - gate
2 - drain (collector)
3 - source (emitter)
4 - drain (collector)

Dim.	Inches Min	Max	Millimeters Min	Max
A	.193	.201	4.90	5.10
A1	.106	.114	2.70	2.90
b	.045	.057	1.15	1.45
b2	.075	.083	1.90	2.10
C	.016	.026	.040	.065
C2	.057	.063	1.45	1.60
D	.543	.551	13.80	14.00
D1	.488	.500	12.40	12.70
E	.624	.632	15.85	16.05
E1	.524	.535	13.30	13.60
e	.215 BSC		5.45 BSC	
H	1.365	1.395	34.67	35.43
L	.780	.800	19.81	20.32
L1	.079	.091	2.00	2.30
L2	.039	.045	1.00	1.15

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IXYS MOSFETS and IGBTs are covered by one or more of the following U.S. patents:
4,835,592 4,881,106 5,017,508 5,049,961 5,187,117 5,486,715
4,850,072 4,931,844 5,034,796 5,063,307 5,237,481 5,381,025

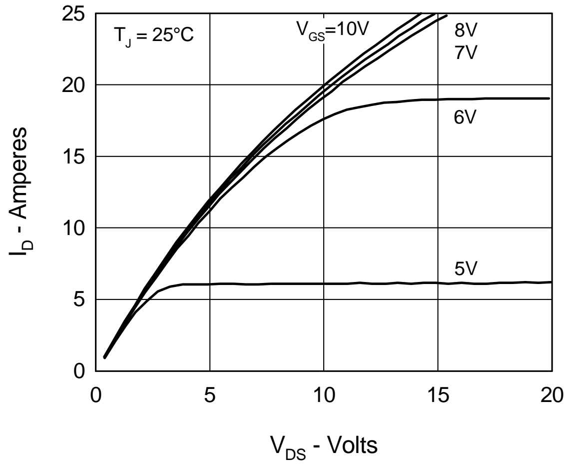

Figure 1. Output Characteristics at 25°C

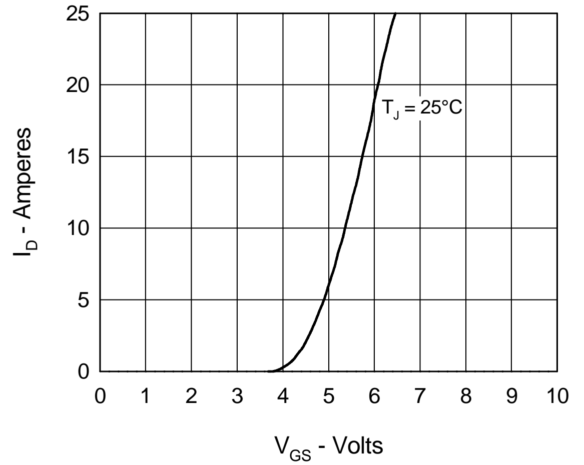

Figure 2. Output Characteristics at 125°C

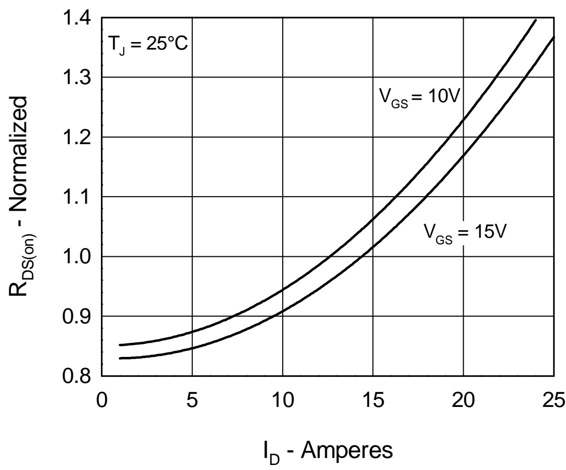

Figure 3. $R_{DS(on)}$ normalized to 0.5 I_{D25} value

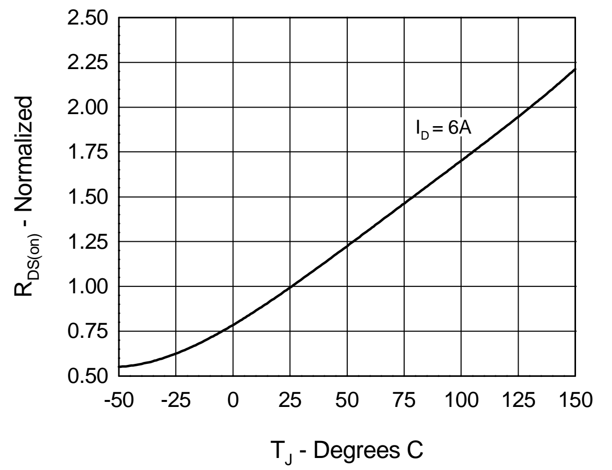

Figure 4. $R_{DS(on)}$ normalized to 0.5 I_{D25} value

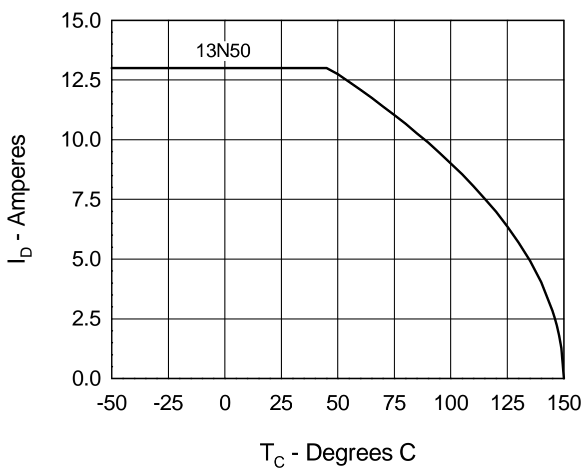

Figure 5. Drain Current vs. Case Temperature

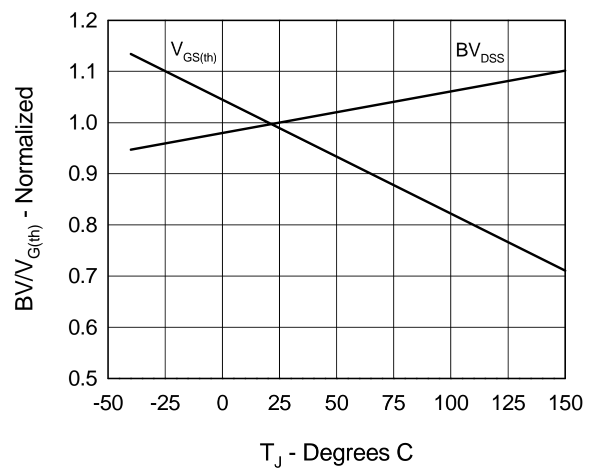

Figure 6. Admittance Curves

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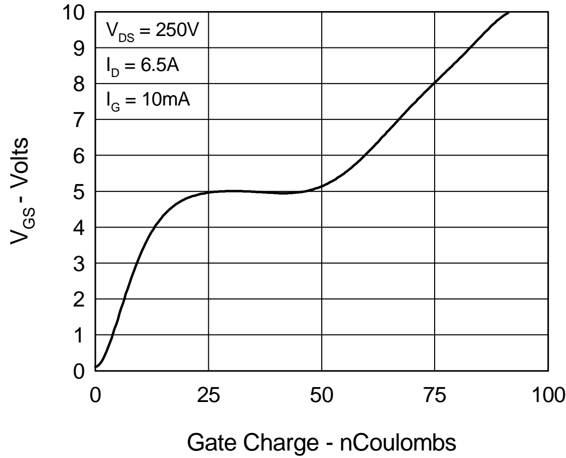

Figure 7. Gate Charge

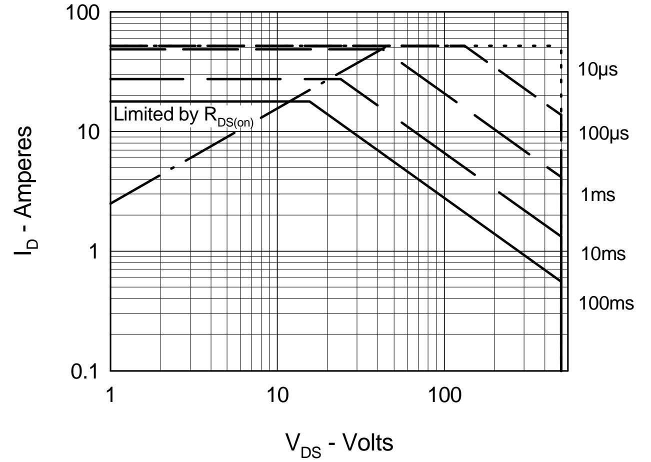

Figure 8. Capacitance Curves

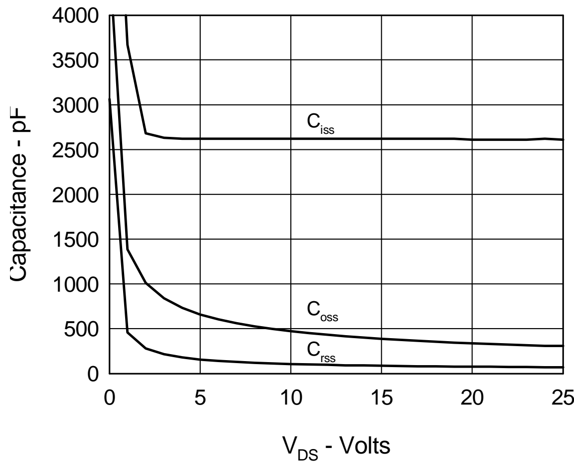

Figure 9. Source Current vs. Source to Drain Voltage

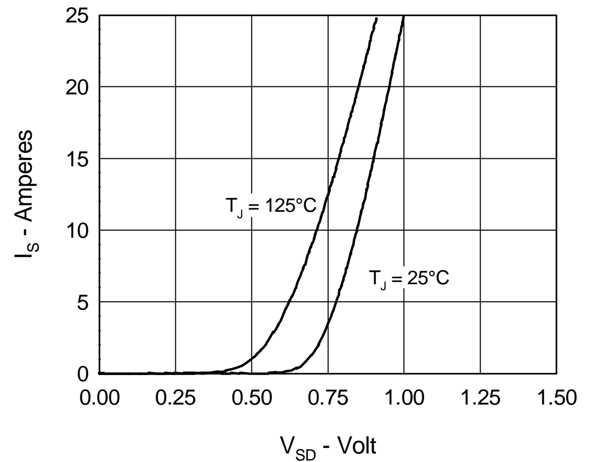

Figure10. Forward Bias Safe Operating Area

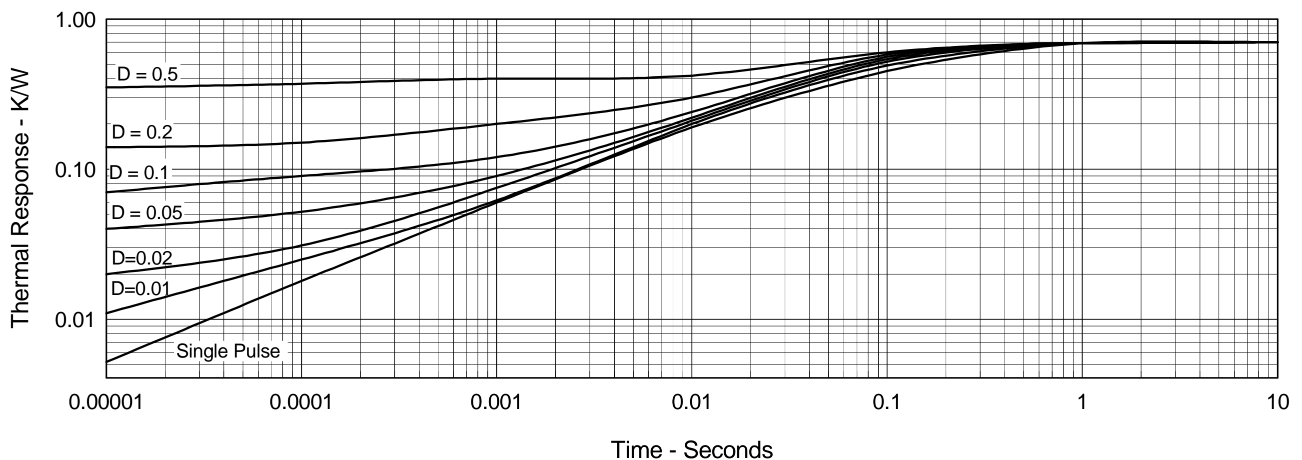

Figure 11. Transient Thermal Resistance

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